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Thermal boundary conductance across heteroepitaxially grown ZnO/GaN interfaces



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Thermal Boundary Conductance Across Heteroepitaxial ZnO/GaN Interfaces: Assessment of the Phonon Gas Model

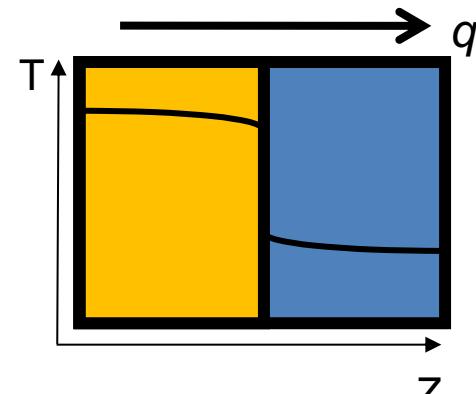
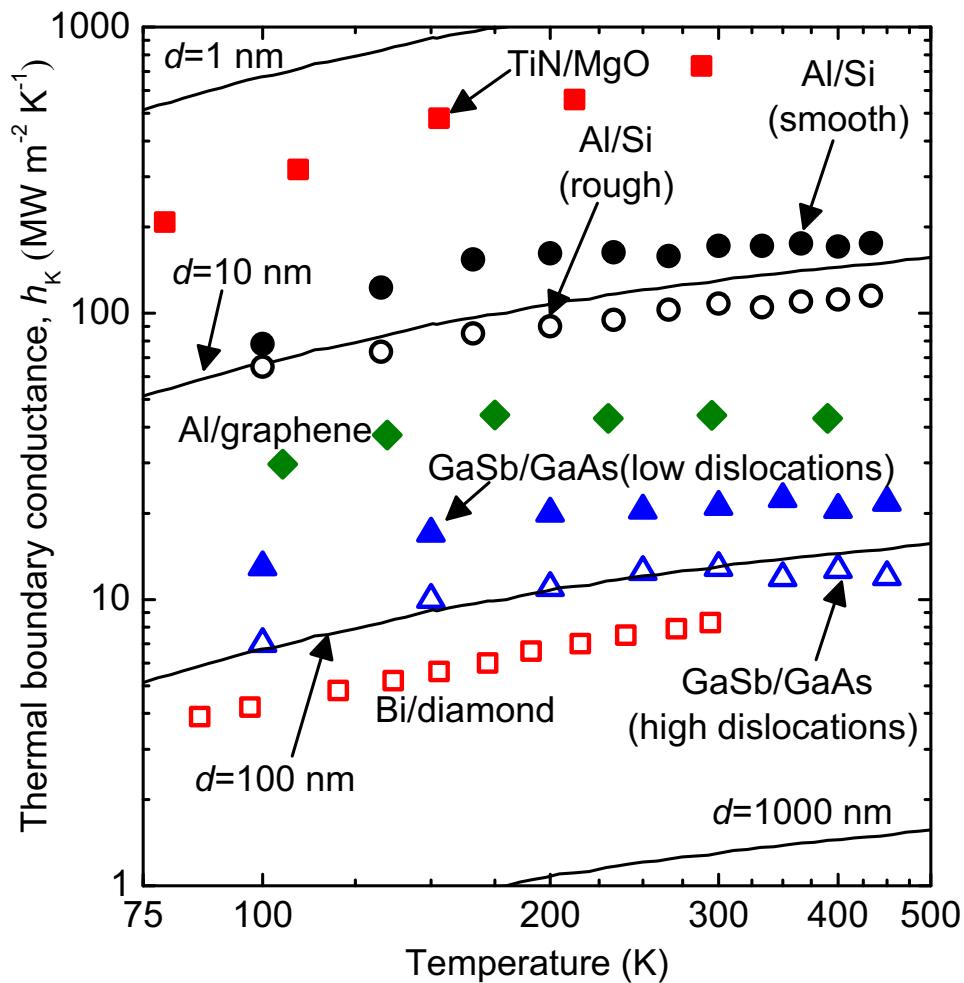
John T. Gaskins,[†] George Kotsonis,[‡] Ashutosh Giri,[§] Shenghong Ju,^{||,⊥} Andrew Rohskopf,[#] Yekan Wang,[▽] Tingyu Bai,[▽] Edward Sachet,[‡] Christopher T. Shelton,[‡] Zeyu Liu,[○] Zhe Cheng,[#] Brian M. Foley,[#] Samuel Graham,^{#,◆} Tengfei Luo,^{○,¶} Asegun Henry,^{#,◆,■} Mark S. Goorsky, Junichiro Shiomi,^{||,⊥} Jon-Paul Maria,[‡] and Patrick E. Hopkins^{*,§,▲,▽}

Dr. John Gaskins
Principle Scientist
UVA

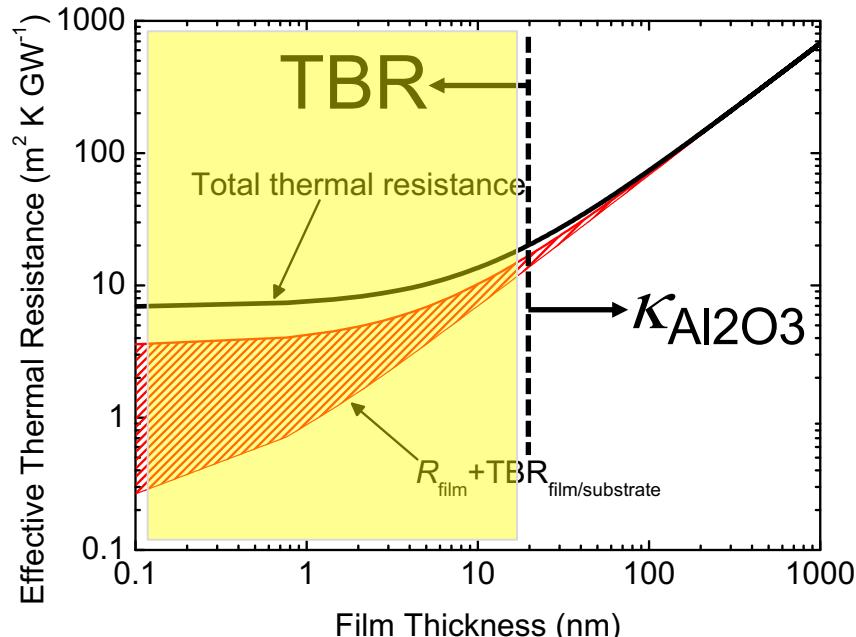


Thermal boundary conductance – nanoscale resistances

$$q = h_K \Delta T = \frac{1}{R_K} \Delta T$$



Ex: Al/ALD Al₂O₃/Si



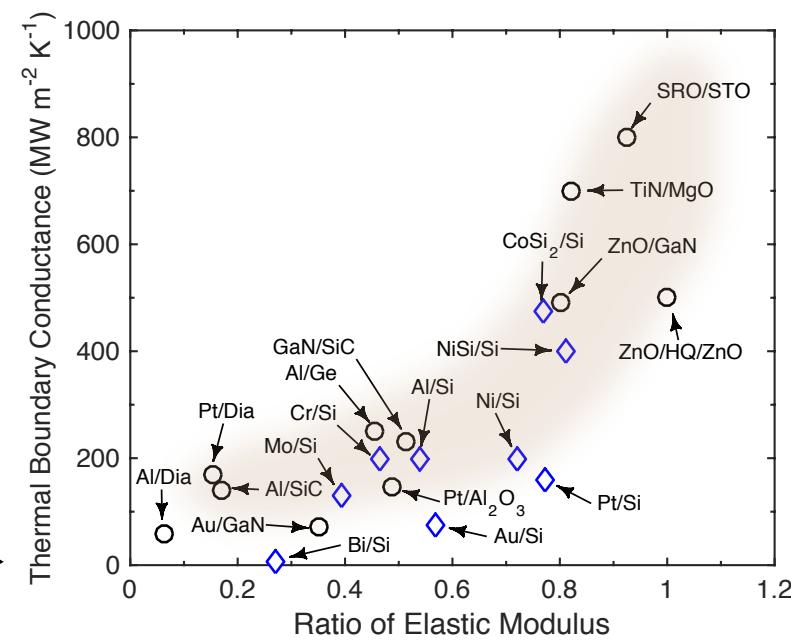
Scott *et al.* APL Materials

6, 058302 (2018)

The basic traditional concept: phonon spectrum matching

$$h_K \propto \int_{\omega} C_{\omega} v_{\omega} \zeta_{\omega} \, d\omega \propto \int_{\omega} \hbar \omega D_{\omega} \frac{\partial f_{\omega}}{\partial T} v_{\omega} \zeta_{\omega} \, d\omega$$

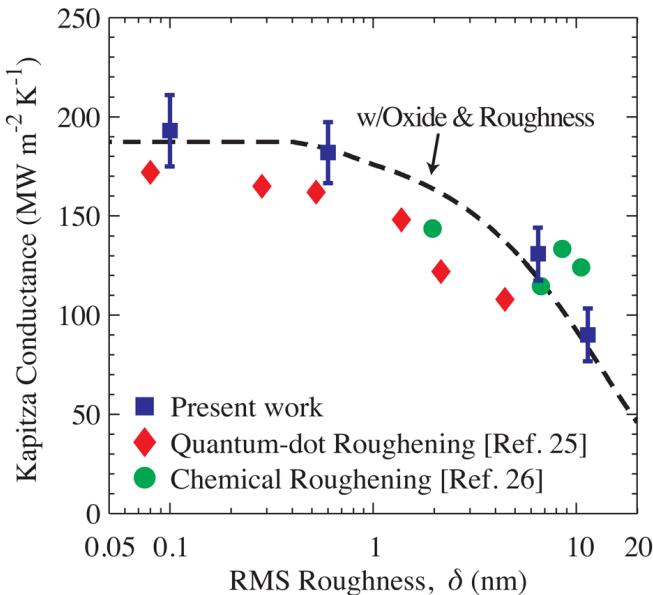
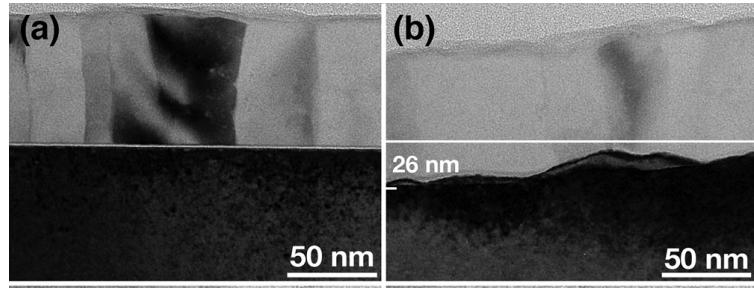
Mismatch Models



Need “high quality” crystalline interfaces to compare to/validate/verify theoretical concepts

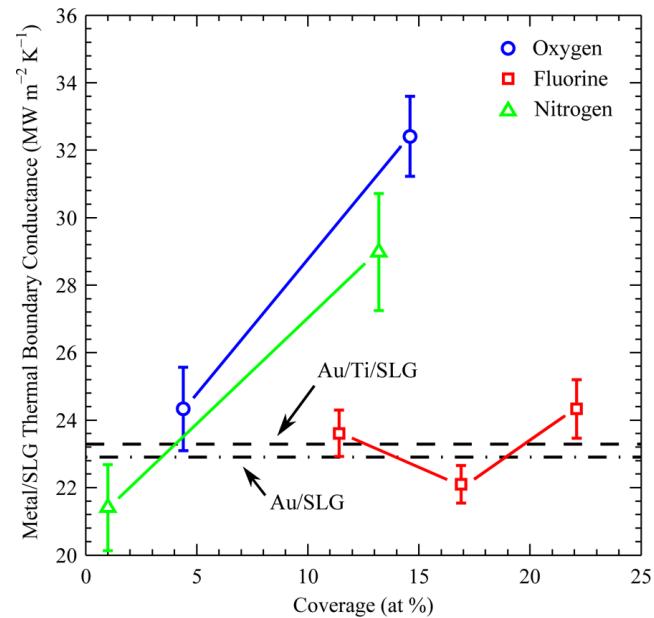
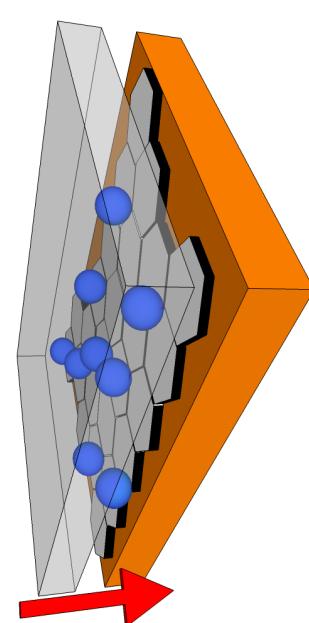
Interfacial imperfections can change in intrinsic TBC

Ex: Al/Si – roughness and native oxide



Duda & Hopkins, *Appl. Phys. Lett.* **100**, 111602 (2012)

Ex: metal/graphene – chemical functionalization



Hopkins *et al.*, *Nano Lett.* **12**, 590 (2012)
Foley *et al.*, *Nano Lett.* **15**, 4876 (2015)

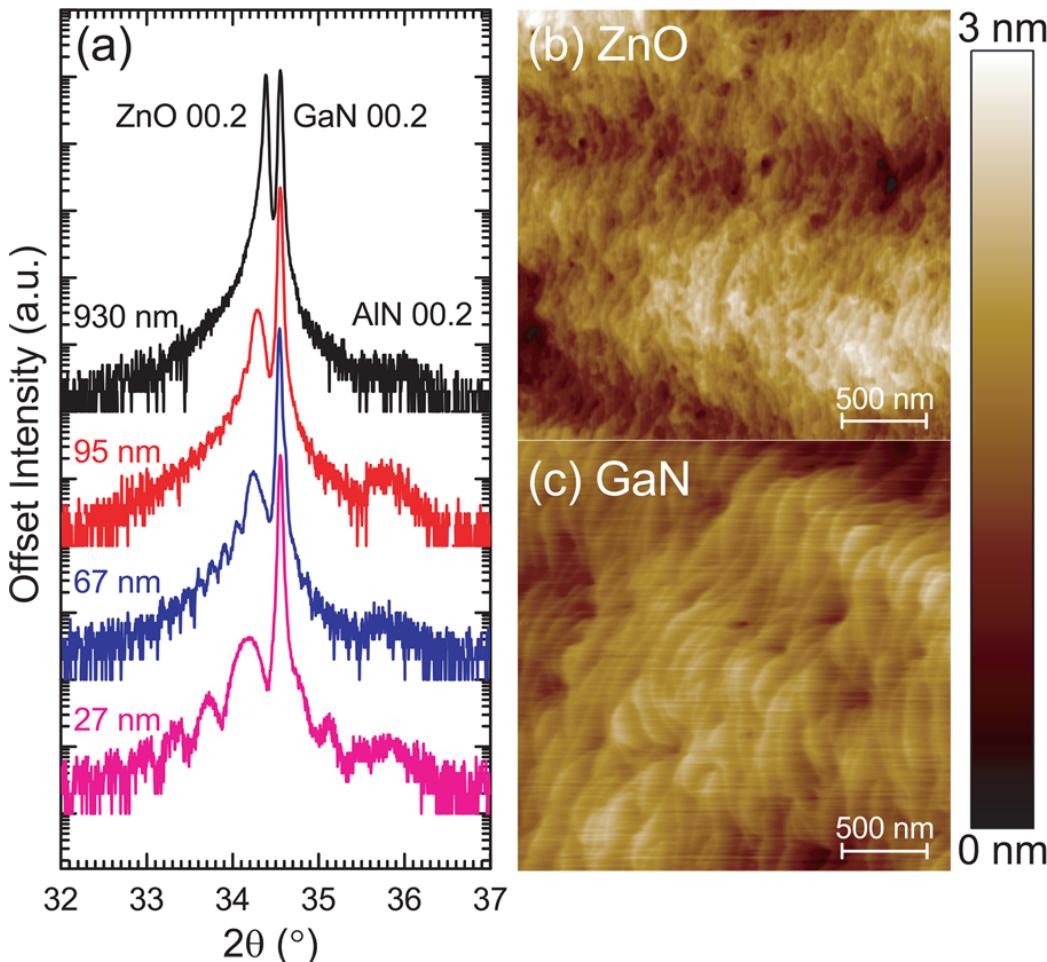
Walton *et al.*, *Surf. & Coat. Tech.* **314**, 148 (2017)

Previous work on “epitaxial” interfaces – and our study

- Need “high quality” crystalline interfaces to compare to/validate/verify theoretical concepts
- Previous “epitaxial” interfaces are metal/non-metal
 - Ex: Bi/Si (Horn-von Hoegen)
 - Ex: TiN/MgO (Cahill)
 - Ex: SrRuO₃/SrTiO₃ (Cahill)
 - Ex: Silicide/Si (Feser, Fisher, Janotti)
- **Our Goal:** Use TDTR to measure TBC across heteroepitaxially grown ZnO on GaN substrates
- *Nearly* ideal interface to study in tandem with theoretical models (DMM, AGF)
- Gaskins *et al.* *Nano Letters* **18**, 7469 (2018)

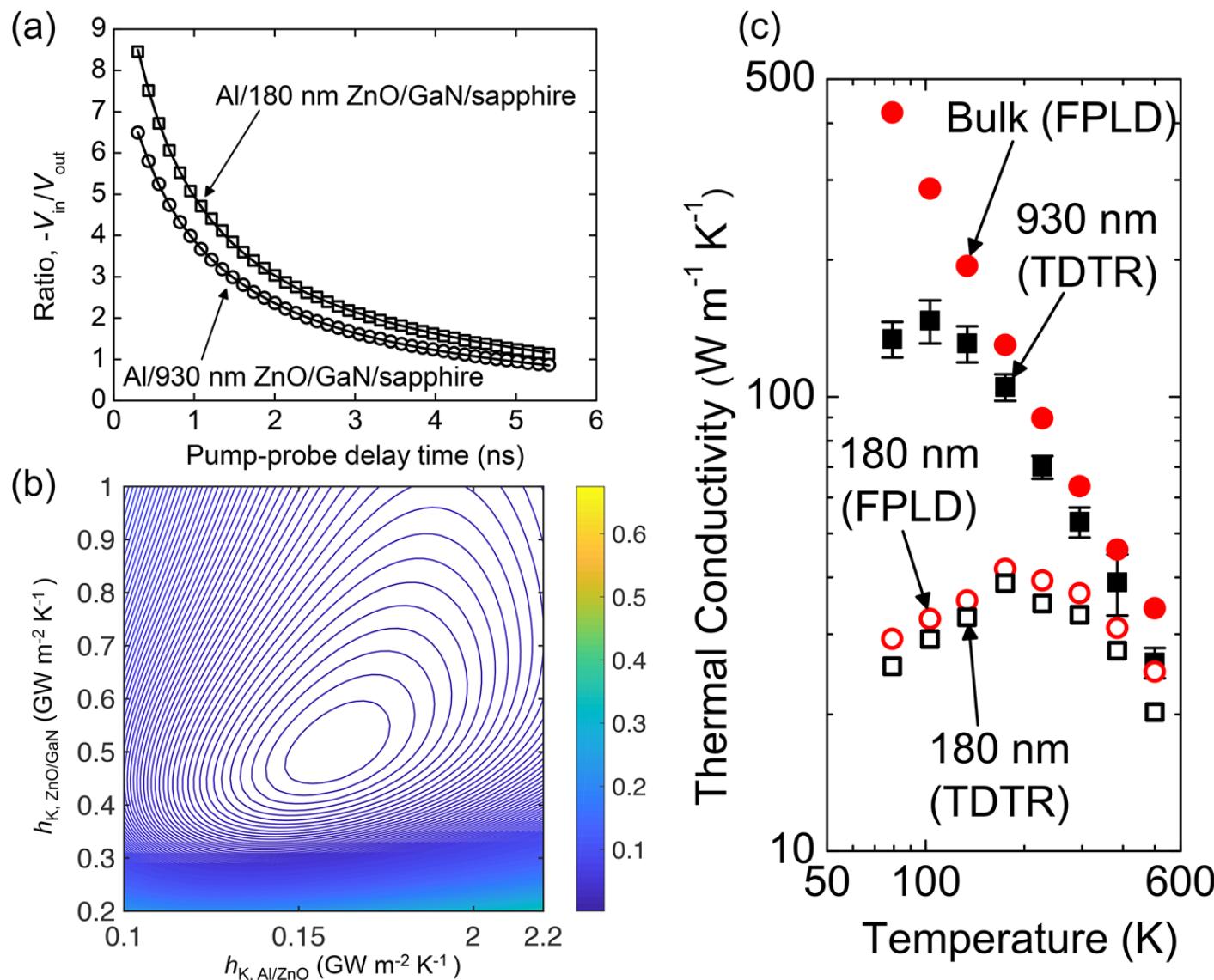
Heteroepitaxial ZnO on Gan/Sapphire

Growth by G. Kotsonis and JP Maria (PSU)

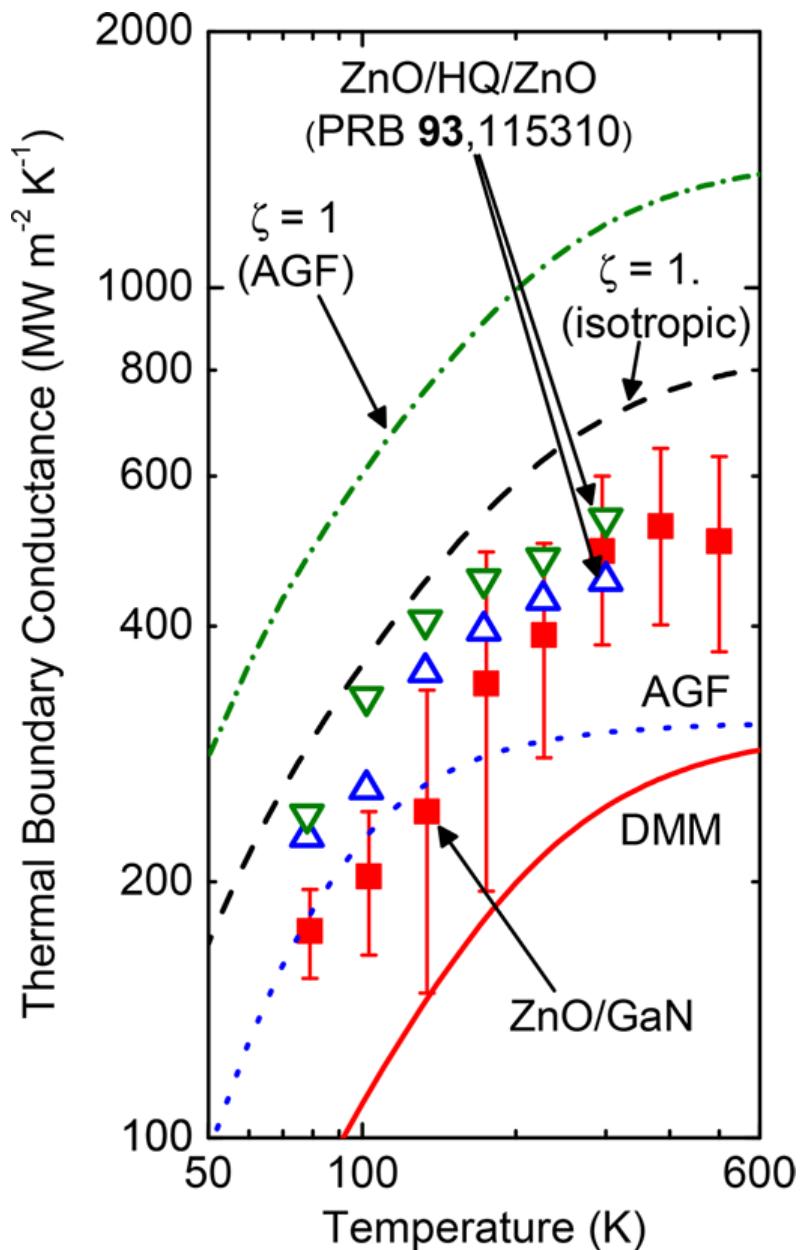


- Thermal conductivity ZnO:
 $d_{\text{ZnO}} = 930 \text{ nm}$
- TBC ZnO/GaN:
 $d_{\text{ZnO}} = 95, 180 \text{ nm}$
- Resistance check of Al/ZnO/GaN:
 $d_{\text{ZnO}} = 5, 10, 19, 27, 42, 66 \text{ nm}$

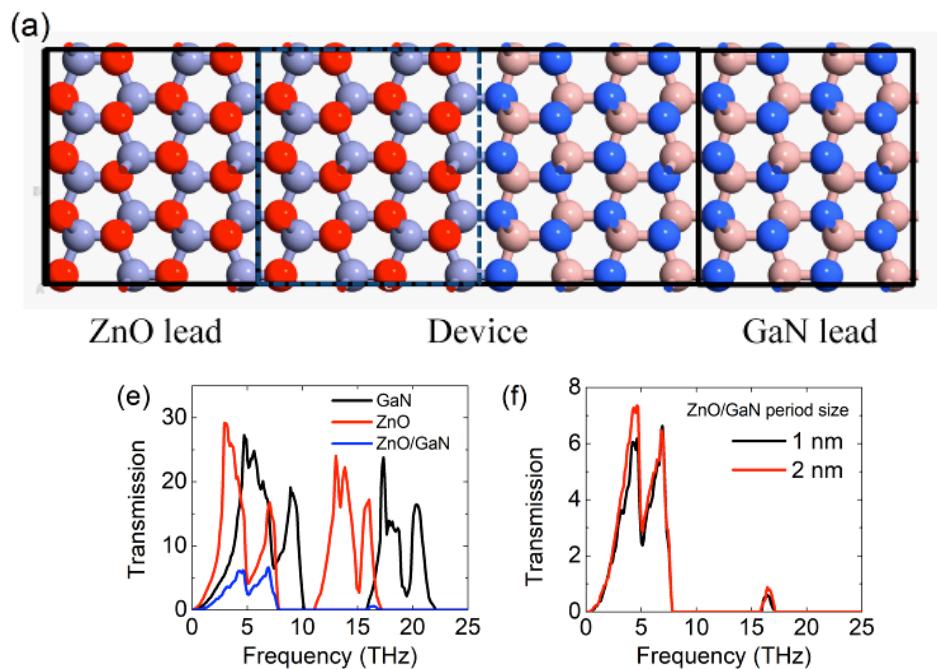
TDTR measurements – uncertainty and layer properties



TBC across ZnO/GaN interfaces

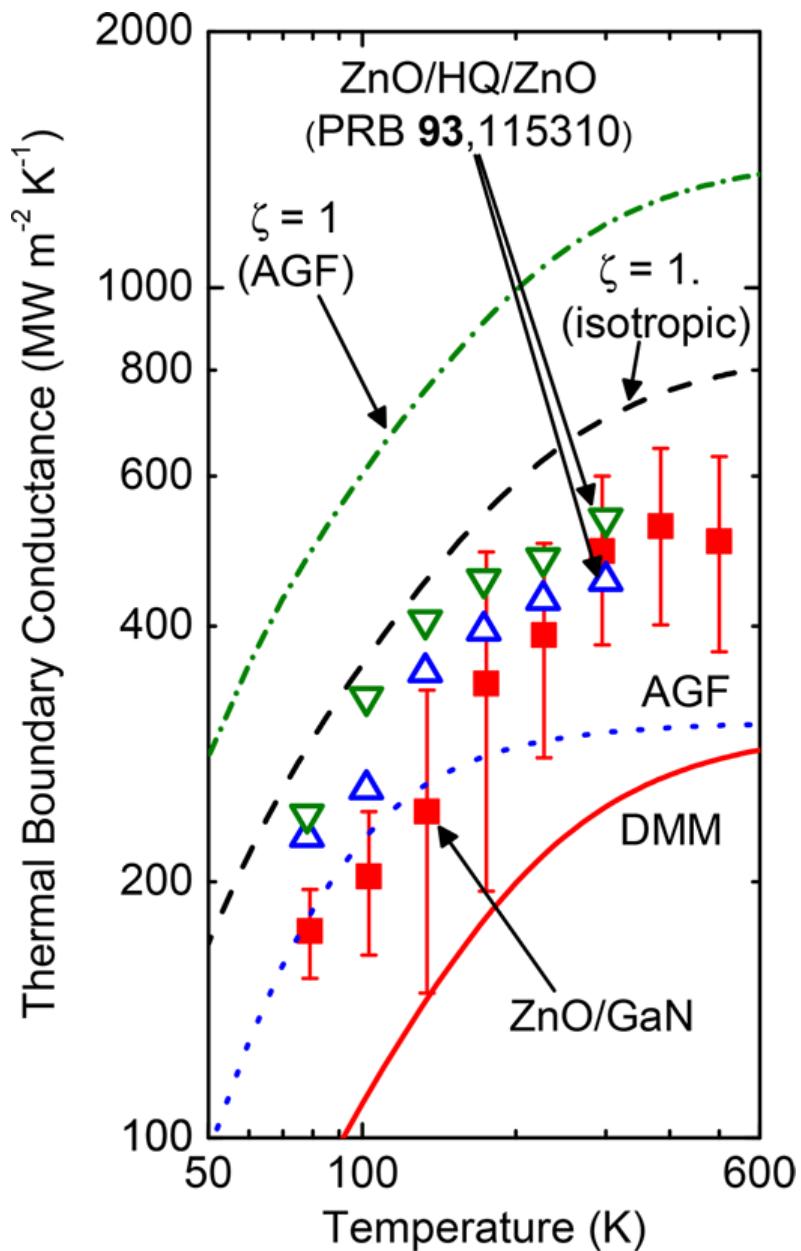


Elastic DMM and AGF can not capture high temperature TBC measurements (calcs from J. Shiomi and A. Henry)

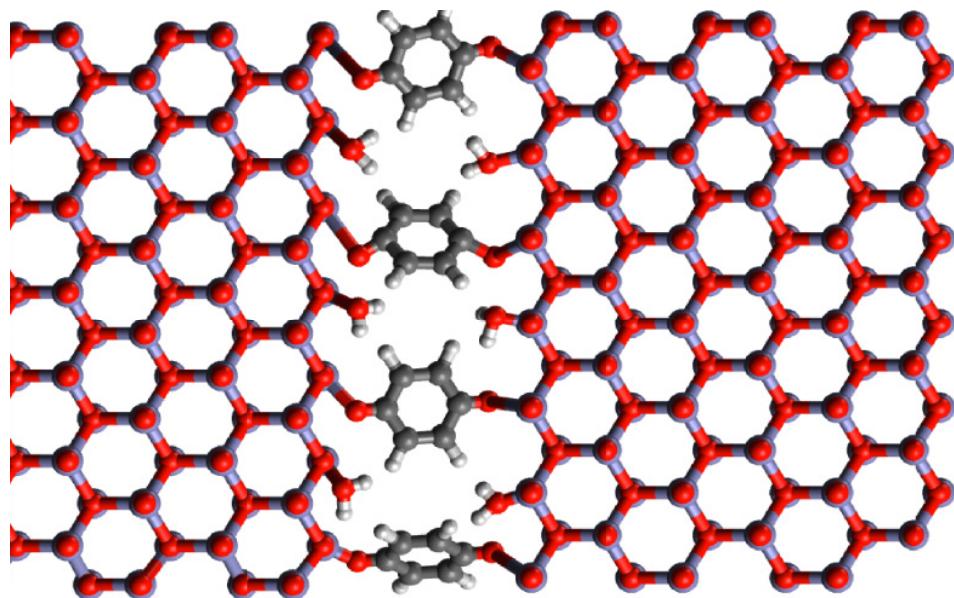


Gaskins *et al.* *Nano Letters*
18, 7469 (2018)

TBC across ZnO/GaN interfaces

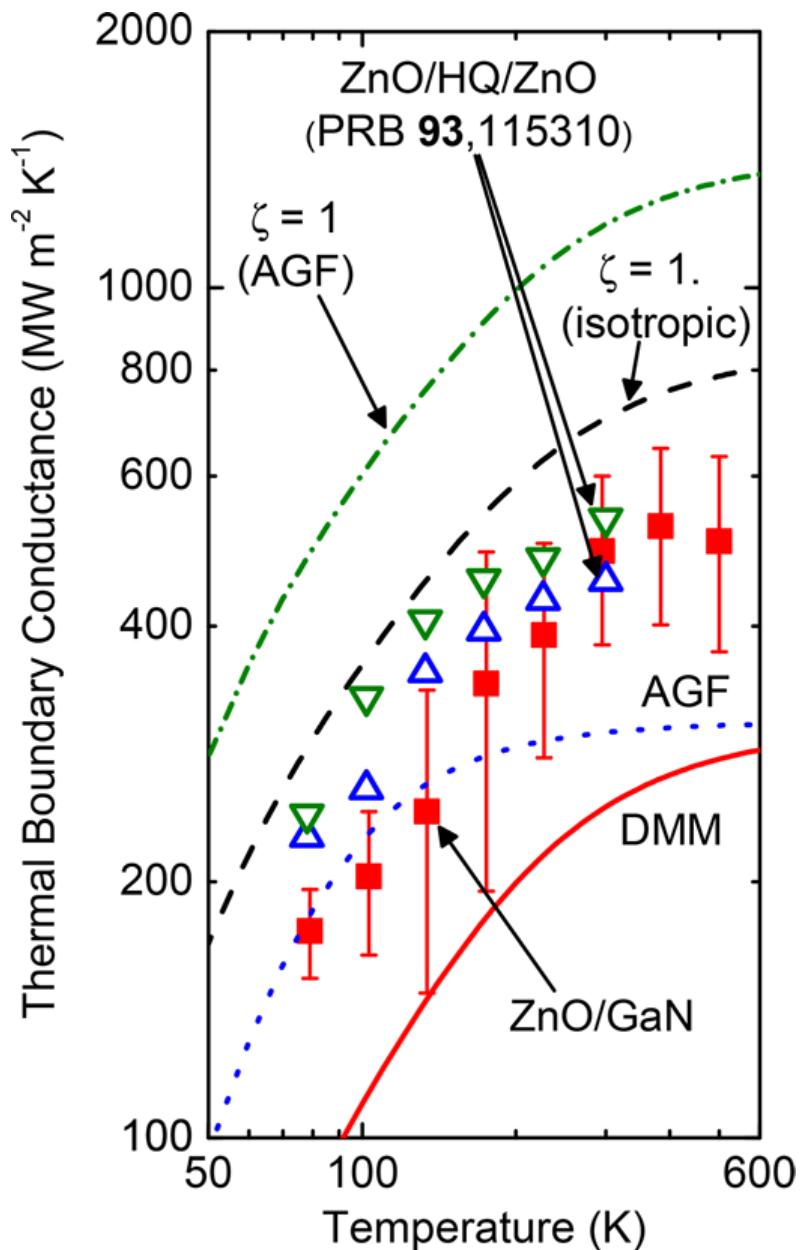


ZnO/GaN TBC similar to
ZnO/HQ/ZnO TBC
demonstrating upper limit to
diffusive scattering

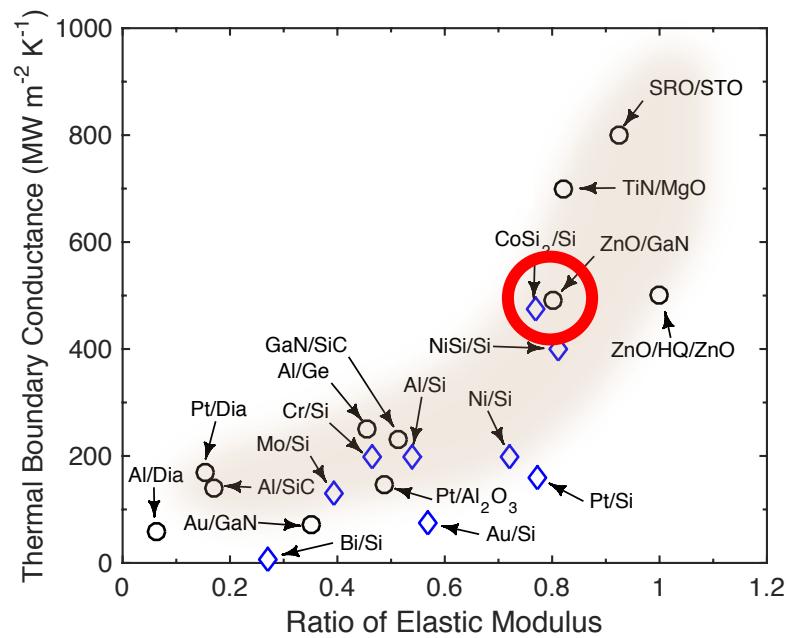


Gaskins *et al.* *Nano Letters*
18, 7469 (2018)

TBC across ZnO/GaN interfaces



ZnO/GaN TBC highest TBC for
crystalline/crystalline non-
metal/non-metal to date

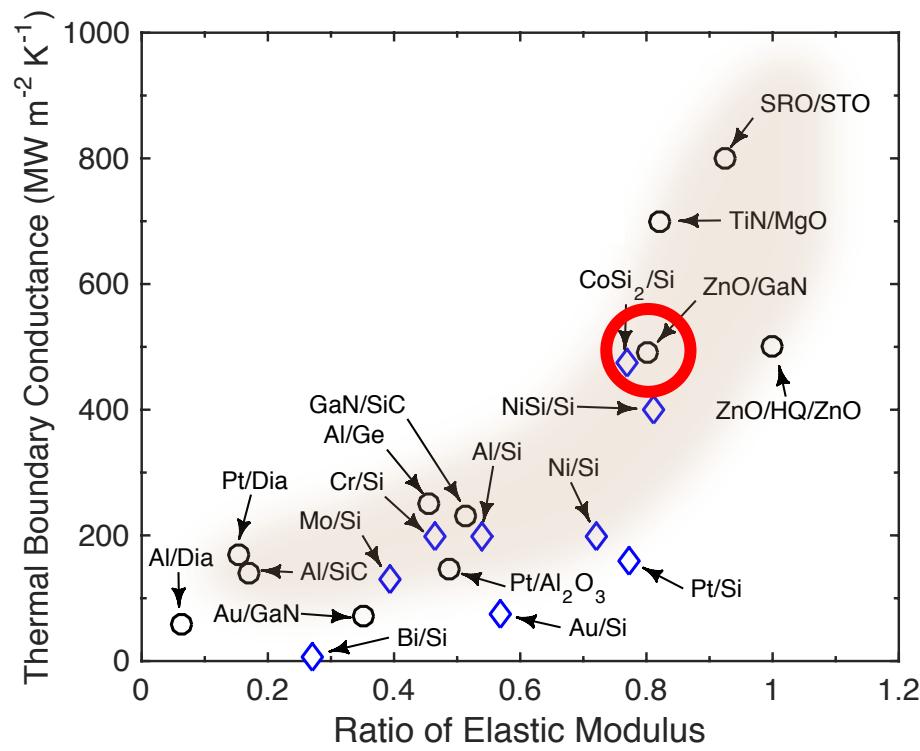


Gaskins *et al.* *Nano Letters*
18, 7469 (2018)

Conclusions

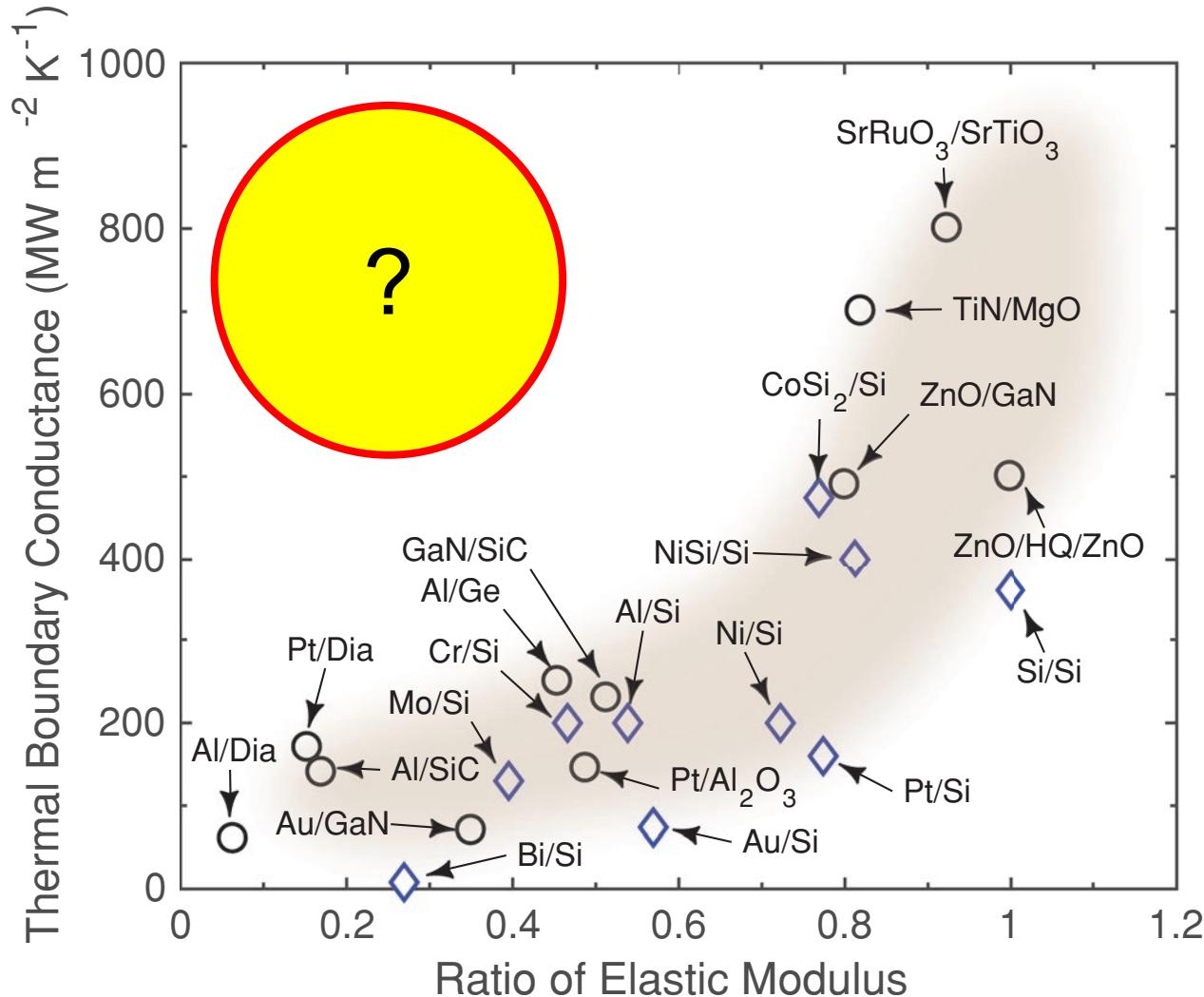
Gaskins *et al.* *Nano Letters* **18**, 7469 (2018)

- ZnO/GaN TBC highest TBC for crystalline/crystalline non-metal/non-metal to date
- Elastic models (semi-classical and atomistic) fail to capture high temp values
- Inelastic scattering? Interfacial modes? Robust landscape of directions can be explored with high quality, well controlled interfaces



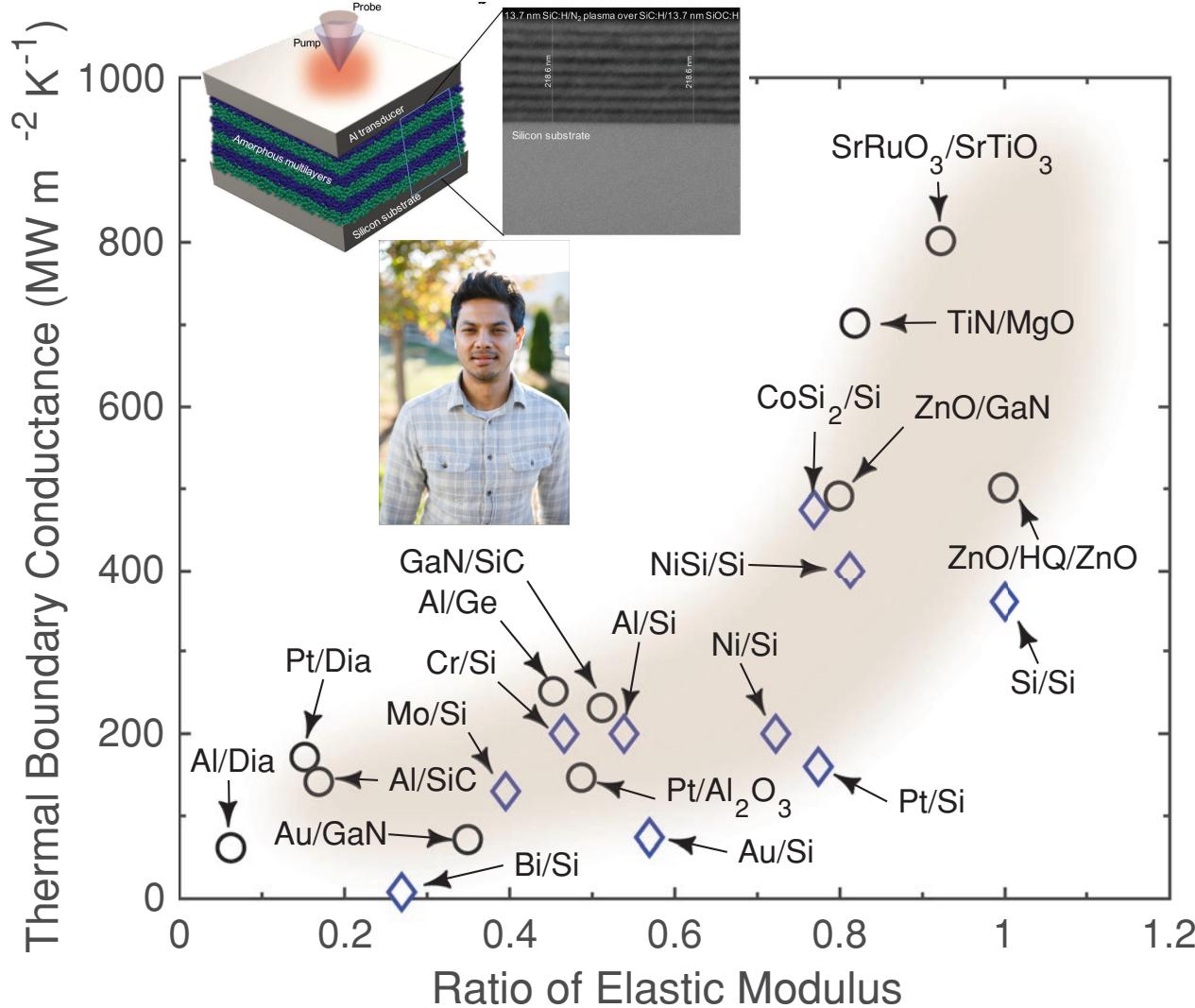
Looking ahead

Giri *et al.* *Advanced Materials* **30**, 1804097 (2018)



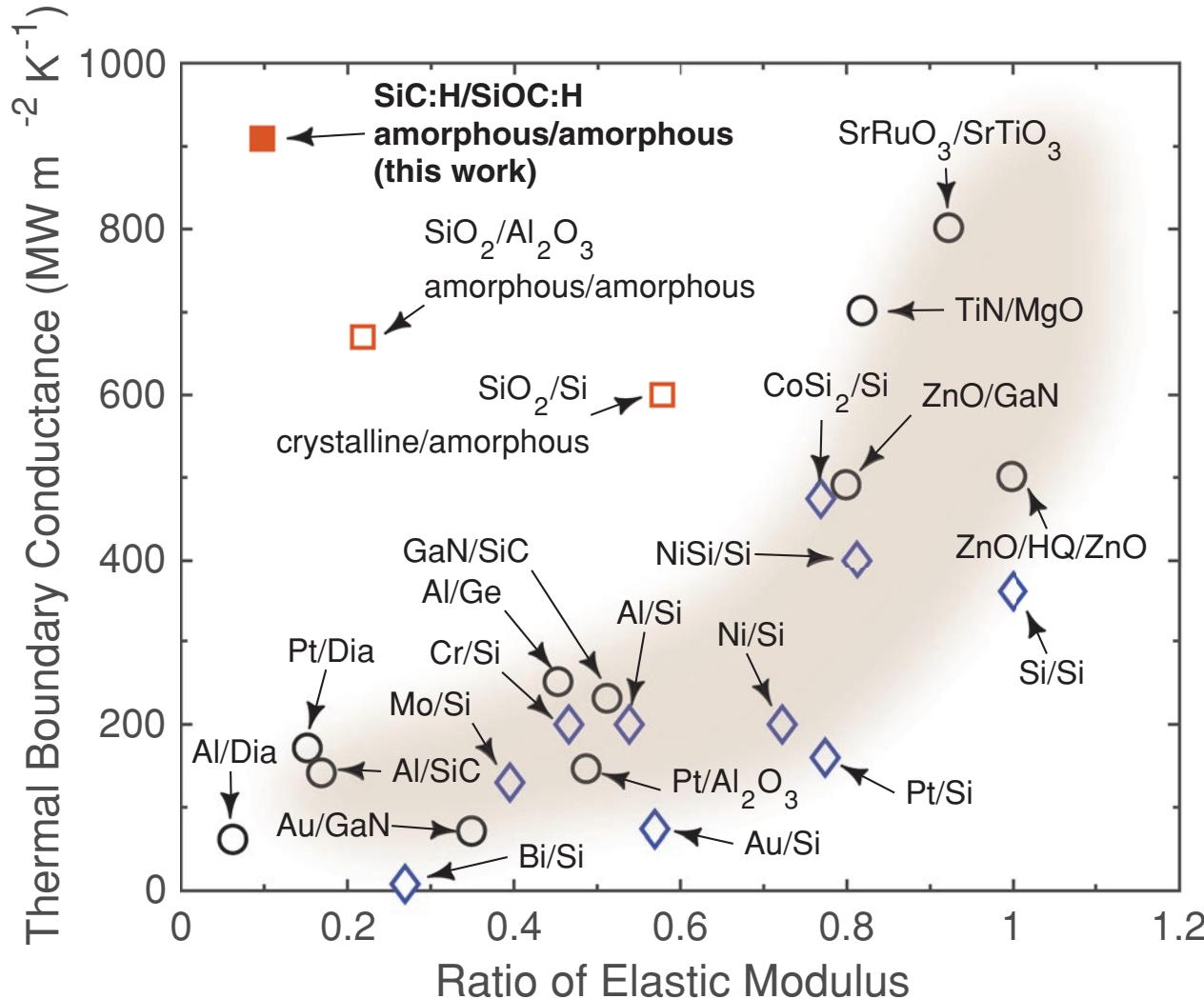
Looking ahead

Giri *et al.* *Advanced Materials* **30**, 1804097 (2018)

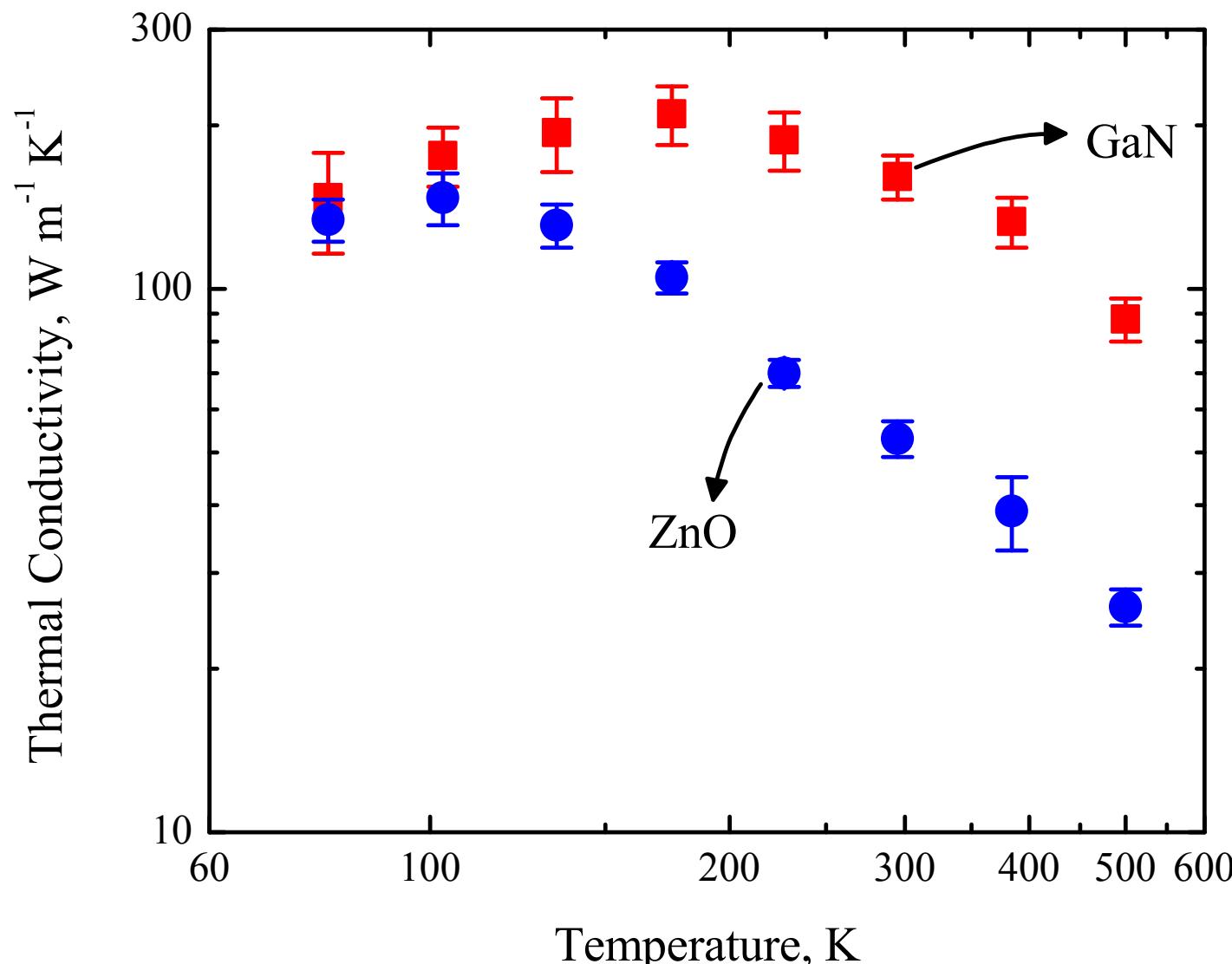


Looking ahead

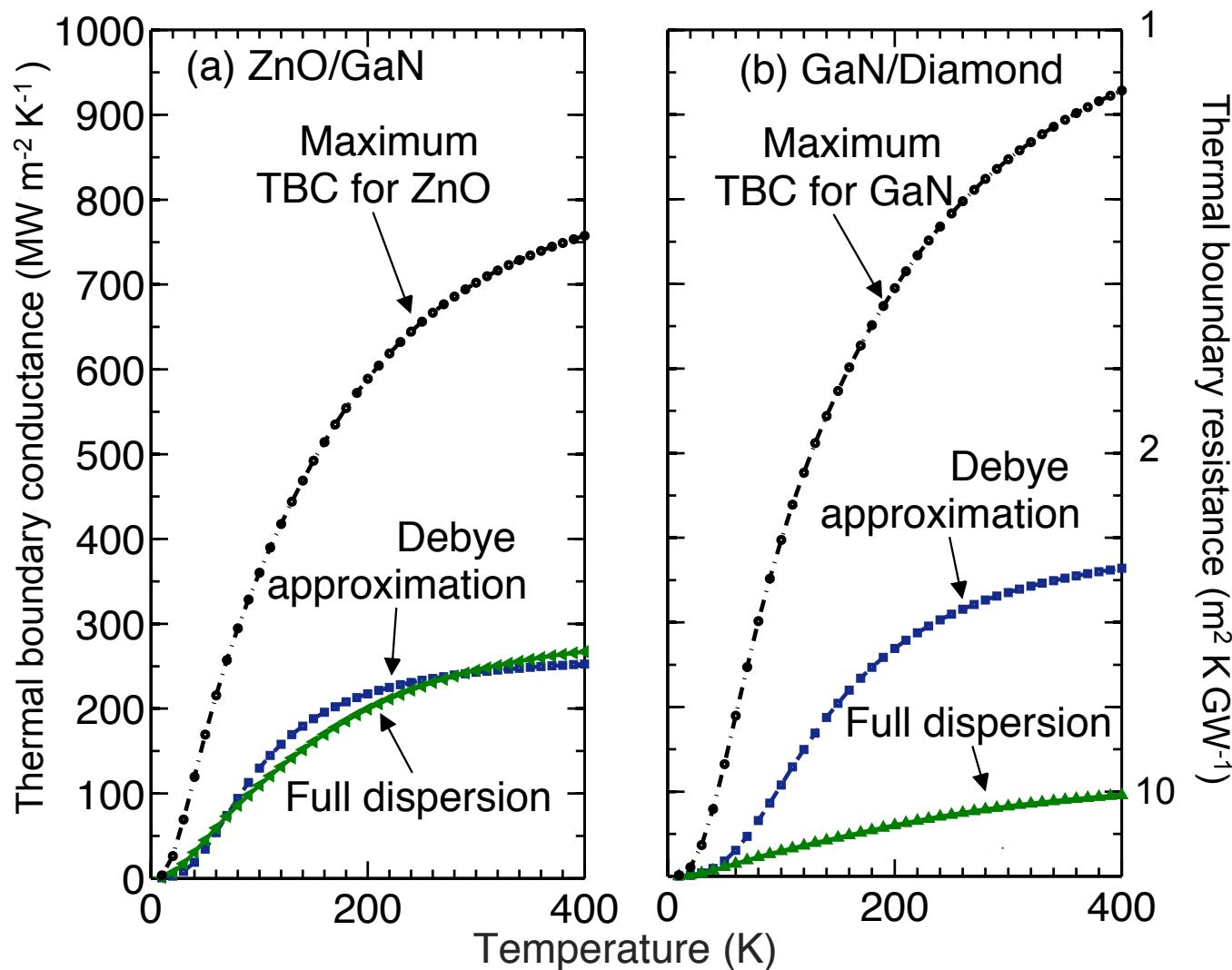
Giri *et al.* *Advanced Materials* **30**, 1804097 (2018)



Thermal conductivity of GaN film on sapphire



In DMM calcs, should use full dispersion



ZnO and GaN dispersion assumptions

